Notice of References Cited Application/Control No. 10/570,022 Applicant(s)/Patent Under Reexamination WAKEFIELD, GLENN MARK Examiner John P. Leubecker 3739 Applicant(s)/Patent Under Reexamination WAKEFIELD, GLENN MARK Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,681,260 A	10-1997	Ueda et al.	600/114
*	В	US-6,240,312 B1	05-2001	Alfano et al.	600/476
*	С	US-2002/0055734 A1	05-2002	Houzego et al.	604/891.1
*	D	US-2002/0198439 A1	12-2002	Mizuno, Hitoshi	600/109
*	Е	US-2003/0020810 A1	01-2003	Takizawa et al.	348/68
*	F	US-2003/0023150 A1	01-2003	Yokoi et al.	600/300
*	G	US-2003/0060734 A1	03-2003	Yokoi et al.	600/593
*	Н	US-2004/0050394 A1	03-2004	Jin, Sungho	128/899
*	ı	US-2004/0138552 A1	07-2004	Harel et al.	600/407
	J	US-			
	K	US-	0		
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
6	R					
	s					
	-				100	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.